

PRODUCT SPECIFICATION

CKM 2013 SERIES

WIRE TO BOARD 2.00mm PITCH CONNECTOR

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REVISION HISTORY:

| REV | REVISION DESCRIPTION | DATE | CREATED/REVISED |
|-----|----------------------------------|-----------|-----------------|
| A | New Created | 2015/4/16 | Jimmy Wang |
| В | Revise Soldering Resistance Info | 2019/10/2 | Jimmy Wang |
| С | | | |
| D | | | |

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1. SCOPE

This specification contains the test requirement of subject connectors when tested under the condition and procedure with terminals crimped on the specified maximum size wire.

2. APPLICABLE STANDARDS

MIL - STD - 202Methods for test of connectors for electronic equipmentMIL - STD - 1344Test methods for electrical connectorsJIS C0020, C0021, C0025JIS C5028JIS C5402UL 1977

3. APPLICABLE SERIES NO: 2013 SERIES

| Product Name | Part No. |
|--------------------|---------------------------------|
| Housing | 2013H-XP-X-XX(-HF) |
| | |
| Terminal | 2013T0X-XX |
| | |
| Wafer Assembly ST. | 2013WV-XX-XX-XXX-HF |
| | |
| Wafer Assembly RA. | 2013WR-XX-XX-XXX-HF |
| | |
| | X or (-HF):Refer to the drawing |

4. PRODUCT SHAPE, DIMENSIONS AND MATERIALS *See attached drawings.

5. ACCOMMODATED P.C. BOARD

- 5.1 Thickness: 0.6 mm (.024 ")~1.2mm (.047 "), 1.6 mm (.063 ")
- 5.2 P.C. Board Layout: See attached drawings

6. RATINGS

- 6.1 Current rating: 2.0A (AWG #24)
- 6.2 Voltage rating: 125V AC, DC

6.3 Temperature range:-25°C to +85°C

6.4 Applicable wire: AWG #24 to #28, Insulation O.D.: 1.60mm Max.

7. PERFORMANCE REQUIREMENTS AND TEST DESCRIPTIONS

The product is designed to meet the electrical, mechanical and environmental performance Requirements as specifics in **8. REQUIREMENTS.**

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| Г | TEST | ITEM | REQUI | REMENT | | PROCEDU | PROCEDURE | | | |
|-------|---|---|--|---|--|--|-----------|----------------------|--|--|
| 8.1 | Exami Produc | nation of | | nents of product Per EIA-364-18 bysical damage. Visual inspection | | | | | | |
| | | | ELEC | CTRICAL REQU | JIRE | MENT | | | | |
| 8.2 | Contao Resista | | 20mΩ Max (Initial) 50mΩ Max (Final) | | | Dry circuit of DC 20 mV max., 10 m max.(JIS C5402 5.4) | | | | |
| 8.3 | Insula Resista | | 1000MΩ Min | | | When applied DC 500 V between adjacent terminal or ground (JIS C5402 5.2/MIL-STD 202 method 301) | | | | |
| 8.4 | Dielec Withst Voltag | anding | No Breakdown and Flashover. | | | When applied AC 800 V 1 minute between adjacent terminal (JIS C5402 5.2/MIL-STD 202 method 302 Cond. B) | | | | |
| | | | MECH | IANICAL REQ | UIRI | EMENT | | | | |
| 8.5 | Termi Tensi streng | Trminal crimp AWG # 24: 3.0kgf Min. AWG # 26: 1.8kgf Min. | | 8kgf Min. | Fix the crimped terminal, apply axial pull out force on the wire at speed rate of 25±3 mm/minute (Basedupon JIS C5402 6.22) *Crimping specification refer to Figure 1 | | | | | |
| 8.6 | Terminal / Housing 5 Retention 1.3kgf Min. Force (For Plug) | | | Retention speed 25±3 mm per minute from housing | | | | | | |
| 8.7 | Matin Un-m force | - | See Item 10 | | Insert and withdraw connector at speed 25 ±3 mm per minute | | | beed of | | |
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| 8.8 Durability | | Contact resistance: Less than twice of initial Dielectric Withstanding Voltage: To pass Para 8.4 | Connector shall be subjected to 30 cycl of insertion and withdrawal (repeatedly by the rate of 10 cycles per minute) | | | | |
|----------------|--|---|--|--|--|--|--|
| 8.9 | Pin retention force (For Header) | 1.0kgf Min. | Push pin from insulator base at speed 25±3 mm per minute | | | | |
| 8.10 | Locking force | 1.0kgf Min. | While withdrawing plug & receptacle without terminal at speed 25±3 mm per minute | | | | |
| | | ENVIRONMENTAL RE(| UIREMENTS | | | | |
| 8.11 | Temperature rise | Final Temp 85°C max. | Then carried the rated current (UL 1977) | | | | |
| 8.12 | Vibration | Appearance: No damage Discontinuity: 50mΩ Max (Final) 1 micro second max. | 1.5 mm 10-55-10 HZ / minute each 2 hours for X , Y and Z directions, (MIL-STD-202,method 201A) | | | | |
| 8.13 | Heat aging | No damage Contact resistance: Less than twice of initial 50mΩ Max (Final) | 85 ±2°C , 96 hours(JIS C0021/ MIL-STD-202,method 108A, condition A) | | | | |
| 8.14 | Humidity | Appearance: No damage Contact resistance: 50mΩ Max (Final) Insulation resistance: 100MΩ Min. | 40±2°C, 90~95% RH, 96 hours measurement must be taken within 30 min. after tested (JIS C0020/MIL-STD-202, method 103 B, condition B) | | | | |

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| 8.15 | | Appearance: No damage Contact resistance: 50mΩ Max (Final) Insulation resistance: 100MΩ Min. | Mated connector shall be set to temperature cycling for 5 cycles of which 1 cycle consists of: a) $+25^{\circ}C \sim 3$ minutes b) $-25^{\circ}C \sim 30$ minutes c) $+25^{\circ}C \sim 30$ minutes d) $+85^{\circ}C \sim 30$ minutes (Based upon JIS C5402 7.2) |
|------|---|--|---|
| 8.16 | Salt spray | Appearance: No damage Contact resistance: 50mΩ Max (Final) | Temperature: 35±2°C Solution: 5±1% Spray time: 48±4 Hours Measurement must be taken after water rinse(JIS C5402 7.1/MIL-STD-202, method 101 D, condition B) |
| 8.17 | Solder ability | Minimum: 95% of immersed area | Lead-Free Process for SMT Type: Soldering time: 3±0.5 second Soldering pot: 245±5°C |
| 8.18 | Resistance to Wave Soldering Heat | No physical damage shall occur | Subject product mounted on printed circuit board to solder bath at 260±5°C for 5±0.5sec |

Crimping Specification:

| 2013T0X-XX Wire Size(AWG) #24 #26 #28 1. CONDUCTOR (mm) CRIMP WIDTH 1.35±0.1 1. CONDUCTOR (mm) CRIMP HEIGHT 1.00~0.90 0.90~0.80 0.80~0.70 2. INSULATION (mm) CRIMP WIDTH 1.55±0.1 CRIMP HEIGHT 1.60 1.50 1.40 CRIMP STRENGTH 3.0Kgf (MIN) 1.8Kgf (MIN) 1.1Kgf (MIN) Figure 1 | | | | 7 | | |
|---|------------------------------|--------------|--------------|----------------|--------------|-----------|
| | Wire Size(A | | #24 #26 | | #28 | |
| | | , | | | 1120 | |
| | 1. CONDUCTOR (mm) | | | | | |
| | | | | | | - |
| | 2. INSULATION (mm) | CRIMP HEIGH | IT 1.60 | 1.50 | 1.40 | - |
| | CRIMP STRE | ENGTH | 3.0Kgf (MIN |) 1.8Kgf (MIN) | 1.1Kgf (MIN) | 1 |
| | | | Figure 1 | | | — |
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10. Mating and Un-mating Force(Remove Latch):

| | At | Initial | At 30th |
|---------|-------------------|----------------------|----------------------|
| PIN No. | Mating (kgf Max.) | Un-mating (kgf Min.) | Un-mating (kgf Min.) |
| 2 | 1.2 | 0.40 | 0.30 |
| 3 | 1.8 | 0.60 | 0.45 |
| 4 | 2.4 | 0.80 | 0.60 |
| 5 | 3.0 | 1.00 | 0.75 |
| 6 | 3.6 | 1.20 | 0.90 |
| 7 | 4.2 | 1.50 | 1.05 |
| 8 | 4.8 | 1.70 | 1.20 |
| 9 | 5.4 | 1.90 | 1.35 |
| 10 | 6.0 | 2.10 | 1.50 |
| 11 | 6.6 | 2.30 | 1.65 |
| 12 | 7.2 | 2.50 | 1.80 |
| 13 | 7.8 | 2.80 | 1.95 |
| 14 | 8.4 | 3.00 | 2.10 |
| 15 | 9.0 | 3.20 | 2.25 |

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11. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE

| | Test Group | | | | | | | | | | |
|--|------------|-----|---|---|--------|--------|---------|-----|-----|-----|-----|
| Test or Examination | Α | В | С | D | Е | F | G | Н | Ι | J | K |
| | | | | | Test S | Sequer | ice (a) | | | | • |
| Examination of Product | 1,8 | 1,7 | 1 | 1 | 1,3 | 1 | 1,5 | 1,5 | 1,4 | 1,3 | 1,3 |
| Contact Resistance | 2,7 | 2,6 | | | | | 2,4 | 2,4 | 2,3 | | |
| Insulation Resitance | | 3,5 | | | | | | | | | |
| Dielectric withstanding Voltage | 3,6 | | | | | | | | | | |
| Terminal crimp Tensile strength | | | 2 | | | | | | | | |
| Terminal / Housing Insertion Force (For Plug) | | | | 2 | | | | | | | |
| Mating & Un-mating force | 4 | | | | | | | | | | |
| Durability | 5 | | | | | | | | | | |
| Temperature Rise | | | | | | 2 | | | | | |
| Vibration | | | | | 2 | | | | | | |
| Heat aging | | | | | | | 3 | | | | |
| Humidity | | 4 | | | | | | | | | |
| Temperature cycling | | | | | | | | 3 | | | |
| Salt spray | | | | | | | | | 3 | | |
| Solder ability | | | | | | | | | | 2 | |
| Resistance to IR reflow heat (SMT) | | | | | | | | | | | 2 |
| Sample Size | 5 | 5 | 5 | 5 | 5 | 5 | 5 | 5 | 5 | 5 | 5 |

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